

Notice of References Cited	Application/Control No. 10/627,782	Applicant(s)/Patent Under Reexamination KAWANISHI ET AL.	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,532,867	07-1996	Hayes et al.	359/329
*	B	US-6,259,836	07-2001	Dodds, David E.	385/24
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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